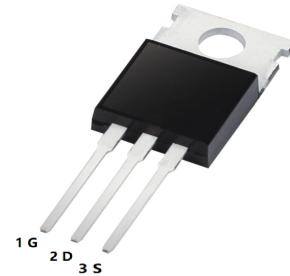


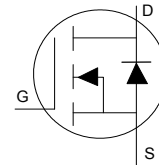
Application

- Brushed Motor drive applications
- Battery powered circuits
- Half-bridge and full-bridge topologies
- Synchronous rectifier applications
- Resonant mode power supplies
- DC/DC and AC/DC converters
- DC/AC Inverters



Benefits

- Improved Gate, Avalanche and Dynamic dV/dt Ruggedness
- Fully Characterized Capacitance and Avalanche SOA
- Enhanced body diode dV/dt and dI/dt Capability
- Lead-Free, RoHS Compliant, Halogen-Free
- $V_{DS} = 100V$
- $I_D = 192A$
- $R_{DS(ON)}(at V_{GS}=10V) < 4.2m\Omega$



Absolute Maximum Rating

Symbol	Parameter	Max.	Units
$I_D @ T_C = 25^\circ C$	Continuous Drain Current, $V_{GS} @ 10V$	192	A
$I_D @ T_C = 100^\circ C$	Continuous Drain Current, $V_{GS} @ 10V$	136	
I_{DM}	Pulsed Drain Current ①	690	
$P_D @ T_C = 25^\circ C$	Maximum Power Dissipation	441	W
	Linear Derating Factor	2.9	W/°C
V_{GS}	Gate-to-Source Voltage	± 20	V
T_J	Operating Junction and	-55 to + 175	°C
T_{STG}	Storage Temperature Range		
	Soldering Temperature, for 10 seconds (1.6mm from case)		
	Mounting Torque, 6-32 or M3 Screw	10 lbf·in (1.1 N·m)	
E_{AS} (Thermally limited)	Single Pulse Avalanche Energy ②	567	mJ
E_{AS} (Thermally limited)	Single Pulse Avalanche Energy ③	1005	
E_{AS} (tested)	Single Pulse Avalanche Energy Tested Value ⑩	240	
I_{AR}	Avalanche Current ①	See Fig 15, 15, 23a, 23b	A
E_{AR}	Repetitive Avalanche Energy ①		mJ

Static @ $T_J = 25^\circ\text{C}$ (unless otherwise specified)

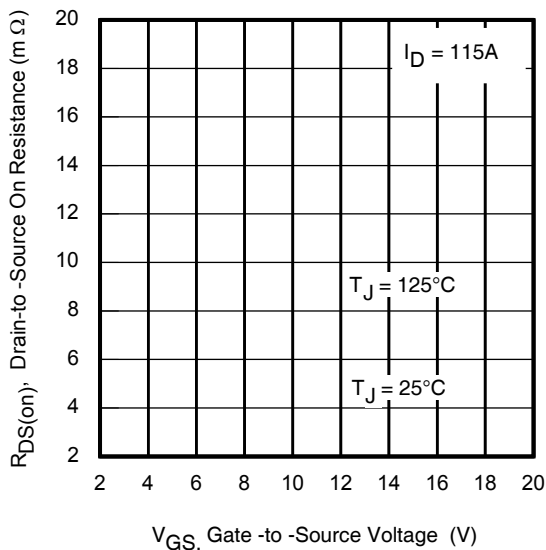
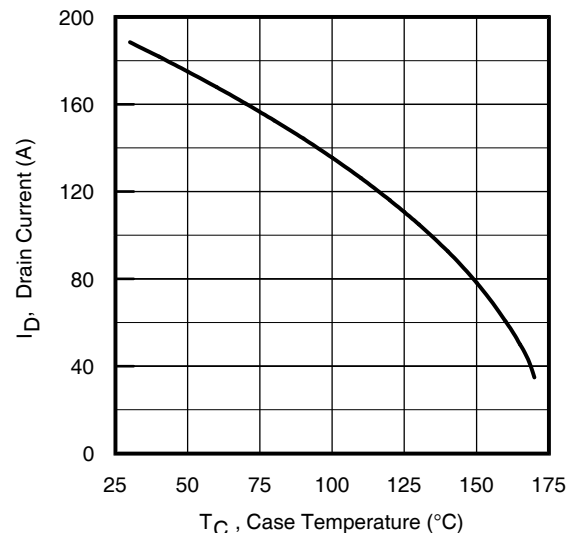
Symbol	Parameter				Typ.	Max.	Units
R _{θJC}	Junction-to-Case ⑦					0.34	°C/W
R _{θCS}	Case-to-Sink, Flat Greased Surface				0.50		
R _{θJA}	Junction-to-Ambient					62	
R _{0JA}	Junction-to-Ambient (PCB Mount) ⑧					40	
Symbol	Parameter	Min.	Typ.	Max.	Units	Conditions	
V _{(BR)DSS}	Drain-to-Source Breakdown Voltage	100			V	V _{GS} = 0V, I _D = 250μA	
ΔV _{(BR)DSS} /ΔT _J	Breakdown Voltage Temp. Coefficient		0.1		V/°C	Reference to 25°C, I _D = 5mA ①	
R _{DS(on)}	Static Drain-to-Source On-Resistance		3.5	4.2	mΩ	V _{GS} = 10V, I _D = 115A	
V _{GS(th)}	Gate Threshold Voltage	2.0		4.0	V	V _{DS} = V _{GS} , I _D = 250μA	
I _{DSS}	Drain-to-Source Leakage Current			20	μA	V _{DS} = 100 V, V _{GS} = 0V	
				250		V _{DS} = 80V, V _{GS} = 0V, T _J = 125°C	
I _{GSS}	Gate-to-Source Forward Leakage			100	nA	V _{GS} = 20V	
	Gate-to-Source Reverse Leakage			-100		V _{GS} = -20V	
R _G	Gate Resistance		2.2		Ω		

Notes:

- ① Repetitive rating; pulse width limited by max. junction temperature.
- ② Limited by T_{Jmax} , starting $T_J = 25^\circ\text{C}$, $L = 86\mu H$, $R_G = 50\Omega$, $I_{AS} = 115A$, $V_{GS} = 10V$.
- ③ $I_{SD} \leq 115A$, $di/dt \leq 1400A/\mu s$, $V_{DD} \leq V_{(BR)DSS}$, $T_J \leq 175^\circ\text{C}$.
- ④ Pulse width $\leq 400\mu s$; duty cycle $\leq 2\%$.
- ⑤ C_{oss} eff. (TR) is a fixed capacitance that gives the same charging time as C_{oss} while V_{DS} is rising from 0 to 80% V_{DSS} .
- ⑥ C_{oss} eff. (ER) is a fixed capacitance that gives the same energy as C_{oss} while V_{DS} is rising from 0 to 80% V_{DSS} .
- ⑦ R_θ is measured at T_J approximately 90°C .
- ⑧ Limited by T_{Jmax} , starting $T_J = 25^\circ\text{C}$, $L = 1.0mH$, $R_G = 50\Omega$, $I_{AS} = 45A$, $V_{GS} = 10V$.
- ⑨ This value determined from sample failure population, starting $T_J = 25^\circ\text{C}$, $L = 86\mu H$, $R_G = 50\Omega$, $I_{AS} = 115A$, $V_{GS} = 10V$.

Dynamic Electrical Characteristics @ $T_J = 25^\circ\text{C}$ (unless otherwise specified)

Symbol	Parameter	Min.	Typ.	Max.	Units	Conditions
g_{fs}	Forward Transconductance	278			S	$V_{DS} = 10\text{V}, I_D = 115\text{A}$
Q_g	Total Gate Charge		170	255	nC	$I_D = 115\text{A}$ $V_{DS} = 50\text{V}$ $V_{GS} = 10\text{V}$
Q_{gs}	Gate-to-Source Charge		46			
Q_{gd}	Gate-to-Drain Charge		45			
Q_{sync}	Total Gate Charge Sync. ($Q_g - Q_{gd}$)		125			
$t_{d(on)}$	Turn-On Delay Time		17		ns	$V_{DD} = 65\text{V}$ $I_D = 115\text{A}$ $R_G = 2.7\Omega$ $V_{GS} = 10\text{V}^{(4)}$
t_r	Rise Time		97			
$t_{d(off)}$	Turn-Off Delay Time		110			
t_f	Fall Time		100			
C_{iss}	Input Capacitance		9500		pF	$V_{GS} = 0\text{V}$ $V_{DS} = 50\text{V}$ $f = 1.0\text{MHz}$, See Fig.TBD $V_{GS} = 0\text{V}, V_{DS} = 0\text{V to } 80\text{V}^{(6)}$ $V_{GS} = 0\text{V}, V_{DS} = 0\text{V to } 80\text{V}^{(5)}$
C_{oss}	Output Capacitance		660			
C_{rss}	Reverse Transfer Capacitance		310			
$C_{oss \text{ eff. (ER)}}$	Effective Output Capacitance (Energy Related)		725			
$C_{oss \text{ eff. (TR)}}$	Output Capacitance (Time Related)		950			
Symbol	Parameter	Min.	Typ.	Max.	Units	Conditions
I_S	Continuous Source Current (Body Diode)			192	A	MOSFET symbol showing the integral reverse p-n junction diode. 
I_{SM}	Pulsed Source Current (Body Diode) ①			690		
V_{SD}	Diode Forward Voltage			1.3	V	$T_J = 25^\circ\text{C}, I_S = 115\text{A}, V_{GS} = 0\text{V}^{(4)}$
dv/dt	Peak Diode Recovery dv/dt ③		18		V/ns	$T_J = 175^\circ\text{C}, I_S = 115\text{A}, V_{DS} = 100\text{V}$
t_{rr}	Reverse Recovery Time		47 55		ns	$T_J = 25^\circ\text{C}$ $V_{DD} = 85\text{V}$ $T_J = 125^\circ\text{C}$ $I_F = 115\text{A}$, $T_J = 25^\circ\text{C}$ $di/dt = 100\text{A}/\mu\text{s}^{(4)}$ $T_J = 125^\circ\text{C}$
Q_{rr}	Reverse Recovery Charge		90 123			
I_{RRM}	Reverse Recovery Current		3.5		A	$T_J = 25^\circ\text{C}$


Fig 1. Typical On- Resistance vs. Gate Voltage

Fig 2. Maximum Drain Current vs. Case Temperature

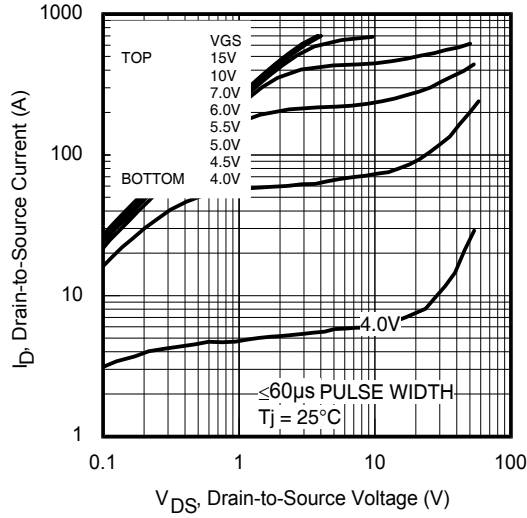


Fig 3. Typical Output Characteristics

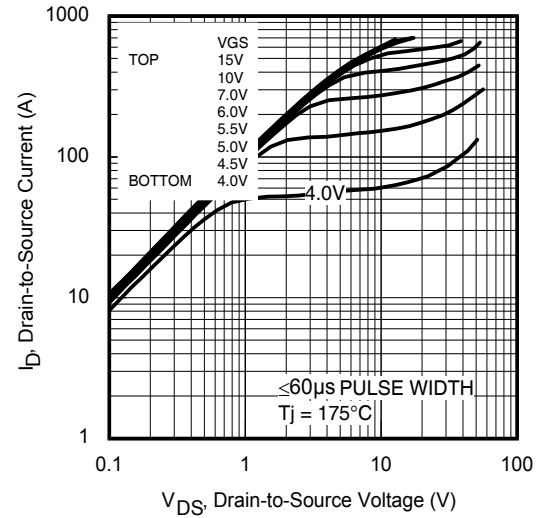


Fig 4. Typical Output Characteristics

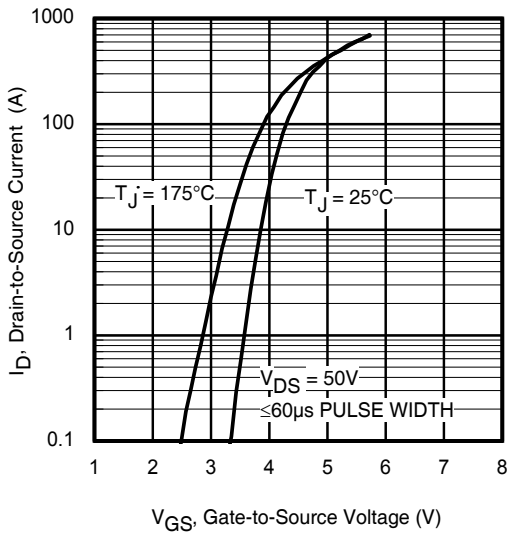


Fig 5. Typical Transfer Characteristics

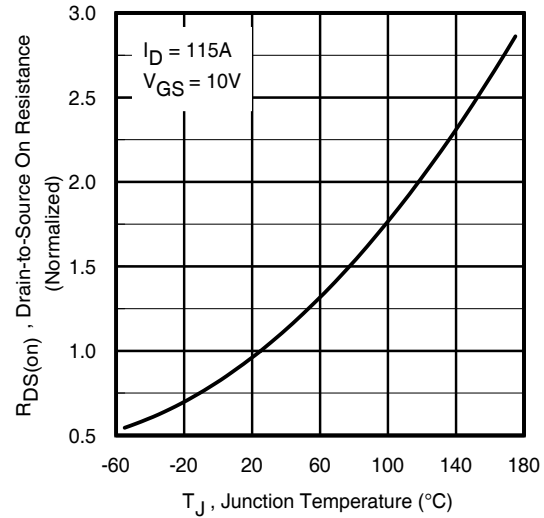


Fig 6. Normalized On-Resistance vs. Temperature

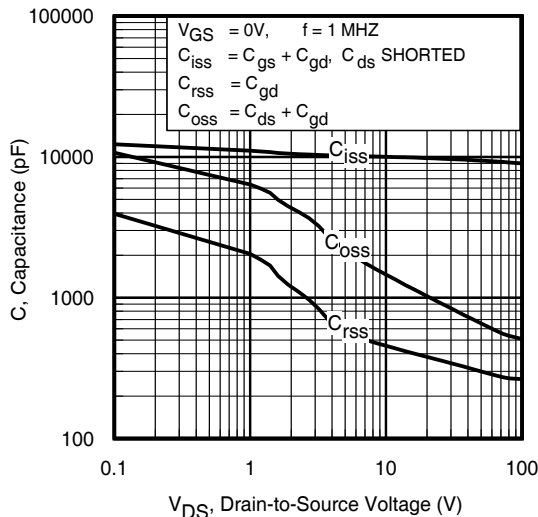


Fig 7. Typical Capacitance vs. Drain-to-Source Voltage

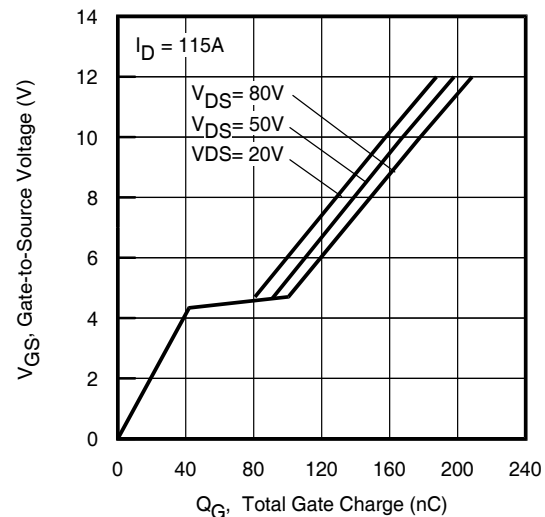


Fig 8. Typical Gate Charge vs. Gate-to-Source Voltage

100 V N-Channel MOSFET

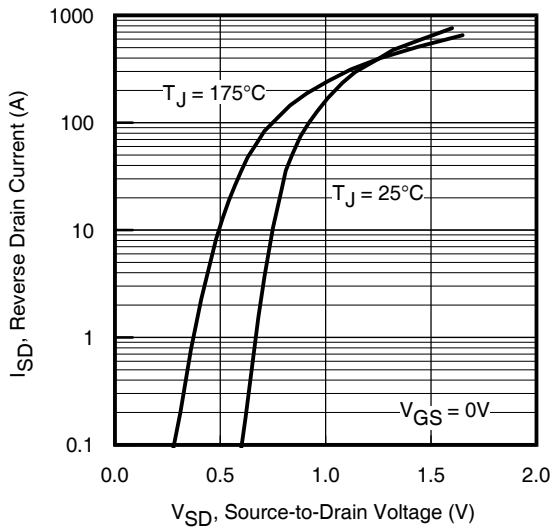


Fig 9. Typical Source-Drain Diode Forward Voltage

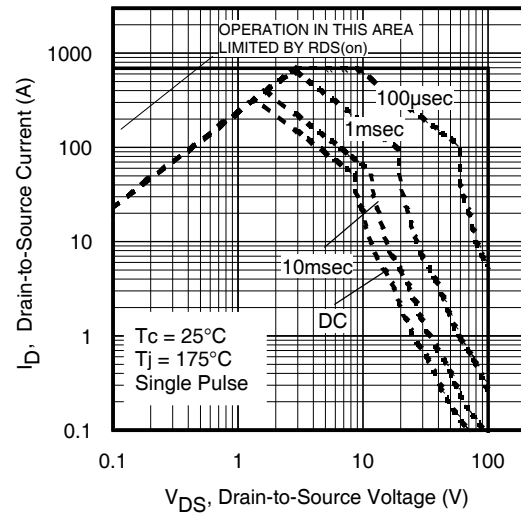


Fig 10. Maximum Safe Operating Area

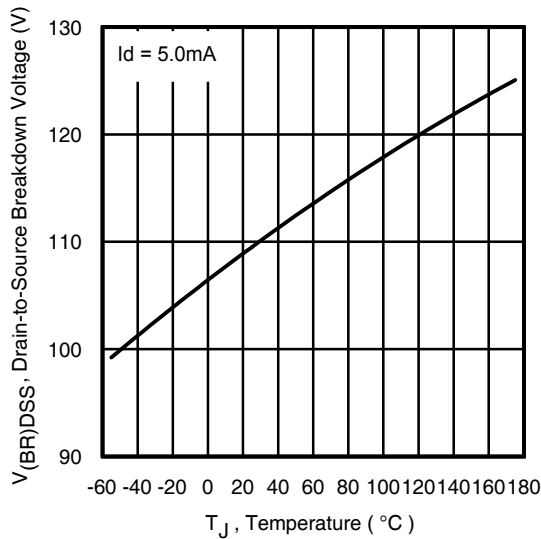


Fig 11. Drain-to-Source Breakdown Voltage

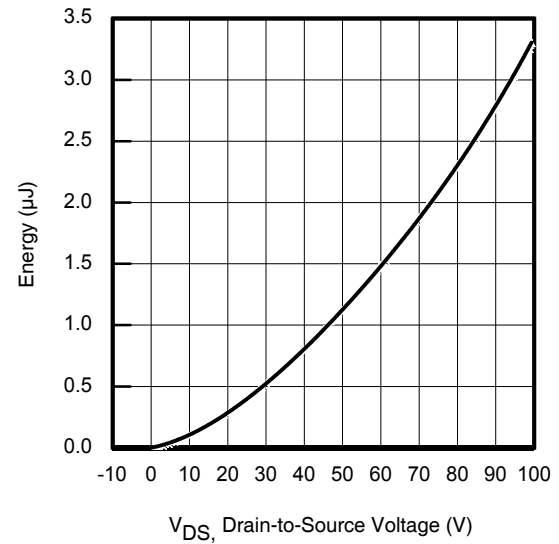


Fig 12. Typical C_{oss} Stored Energy

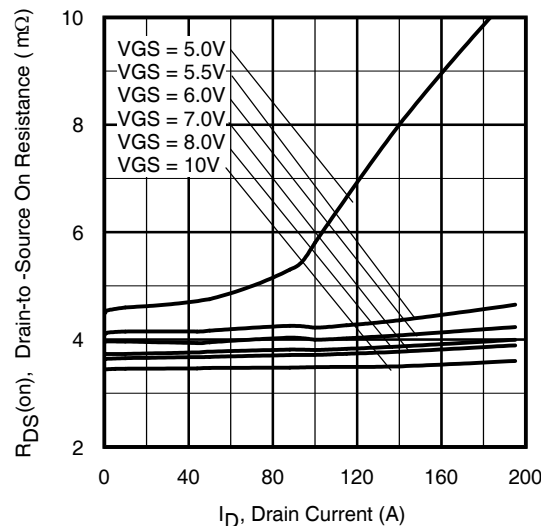


Fig 13. Typical On-Resistance vs. Drain Current

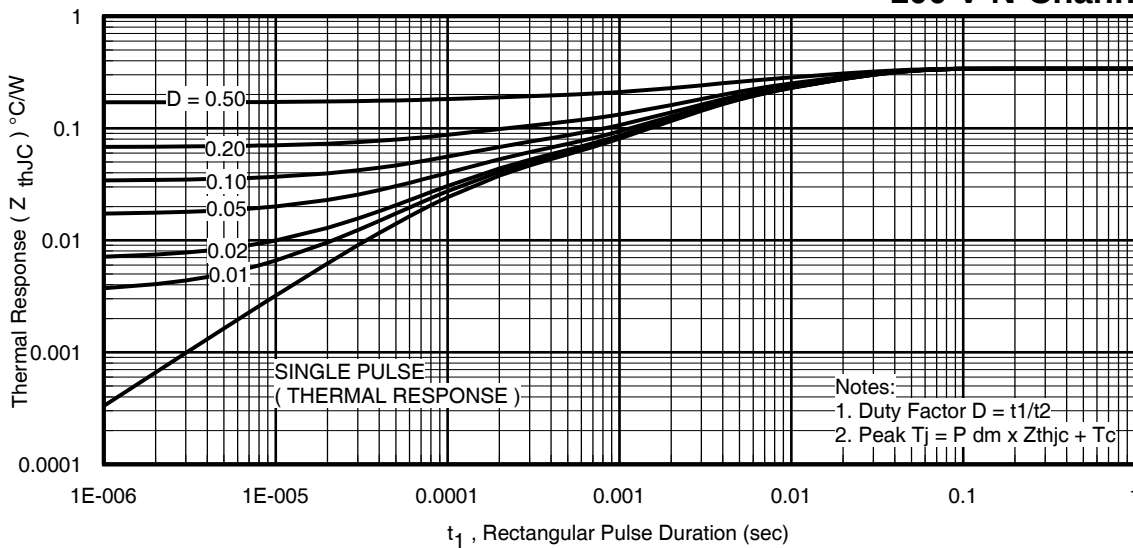


Fig 14. Maximum Effective Transient Thermal Impedance, Junction-to-Case

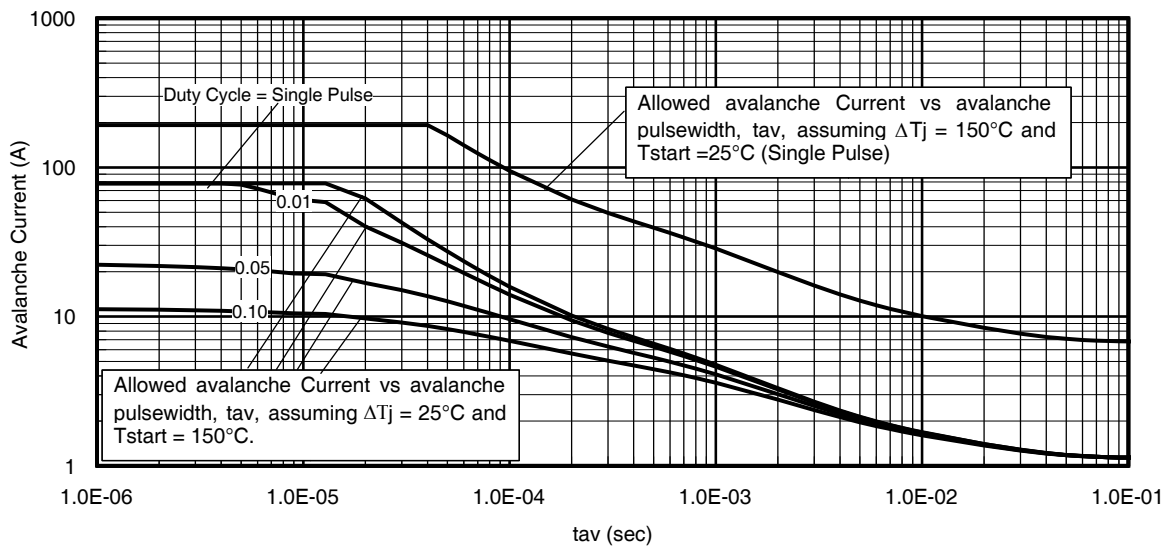


Fig 15. Avalanche Current vs. Pulse Width

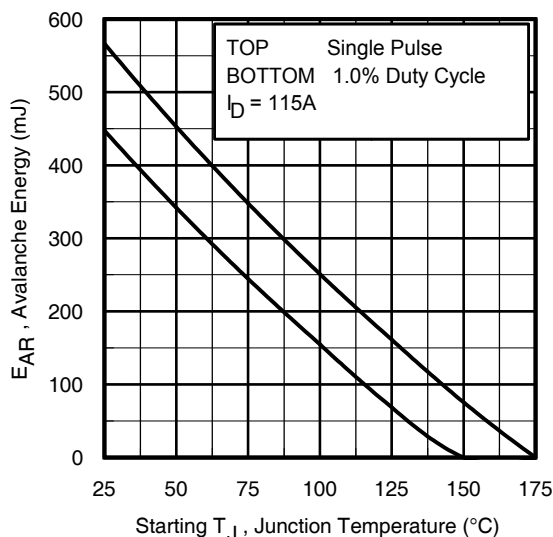


Fig 16. Maximum Avalanche Energy vs. Temperature

Notes on Repetitive Avalanche Curves , Figures 15, 16:

1. Avalanche failures assumption:
Purely a thermal phenomenon and failure occurs at a temperature far in excess of T_{jmax} . This is validated for every part type.
2. Safe operation in Avalanche is allowed as long as T_{jmax} is not exceeded.
3. Equation below based on circuit and waveforms shown in Figures 23a, 23b.
4. $P_{D(ave)}$ = Average power dissipation per single avalanche pulse.
5. BV = Rated breakdown voltage (1.3 factor accounts for voltage increase during avalanche).
6. I_{av} = Allowable avalanche current.
7. ΔT = Allowable rise in junction temperature, not to exceed T_{jmax} (assumed as 25°C in Figure 14, 15).
 t_{av} = Average time in avalanche.
 D = Duty cycle in avalanche = $t_{av} \cdot f$
 $Z_{thJC}(D, t_{av})$ = Transient thermal resistance, see Figures 14)
 $P_{D(ave)} = 1/2 (1.3 \cdot BV \cdot I_{av}) = \Delta T / Z_{thJC}$
 $I_{av} = 2\Delta T / [1.3 \cdot BV \cdot Z_{th}]$
 $E_{AS(AR)} = P_{D(ave)} \cdot t_{av}$

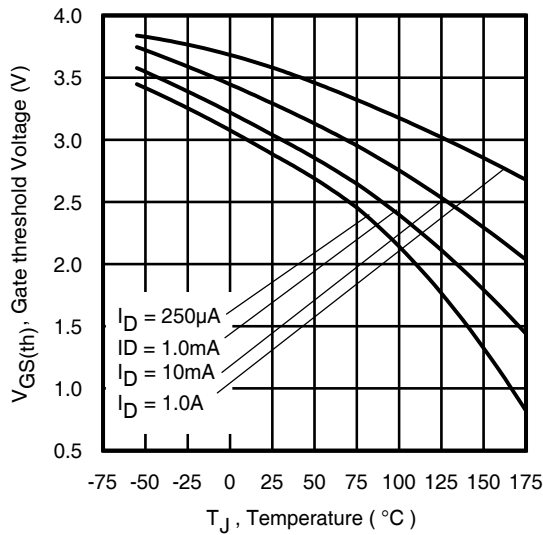


Fig 17. Threshold Voltage vs. Temperature

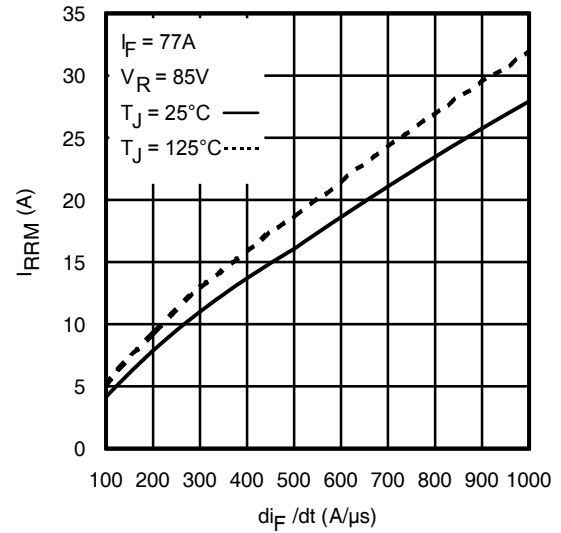


Fig 18. Typical Recovery Current vs. dif/dt

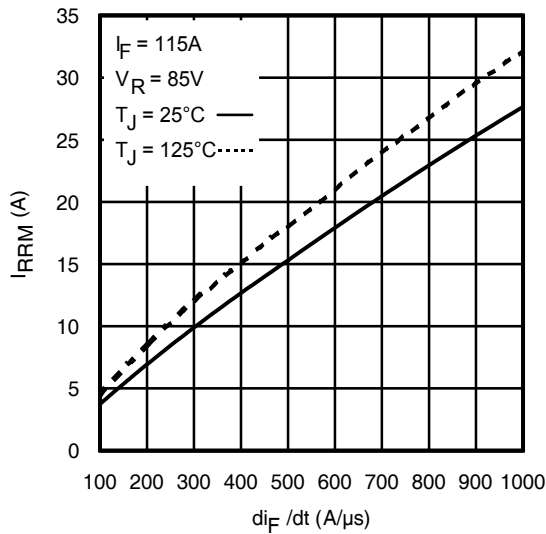


Fig 19. Typical Recovery Current vs. dif/dt

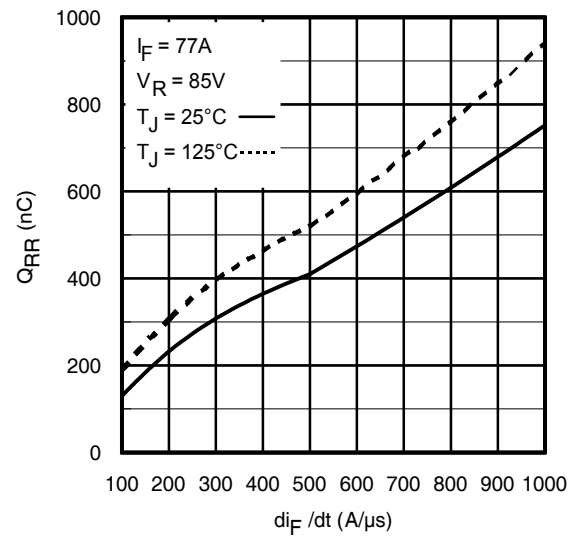


Fig 20. Typical Stored Charge vs. dif/dt

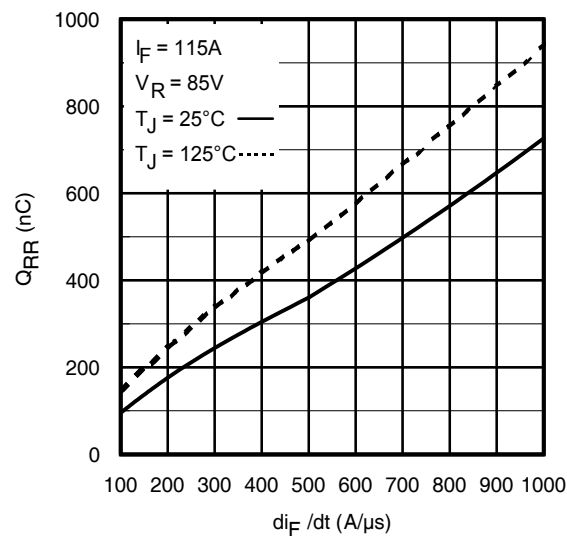
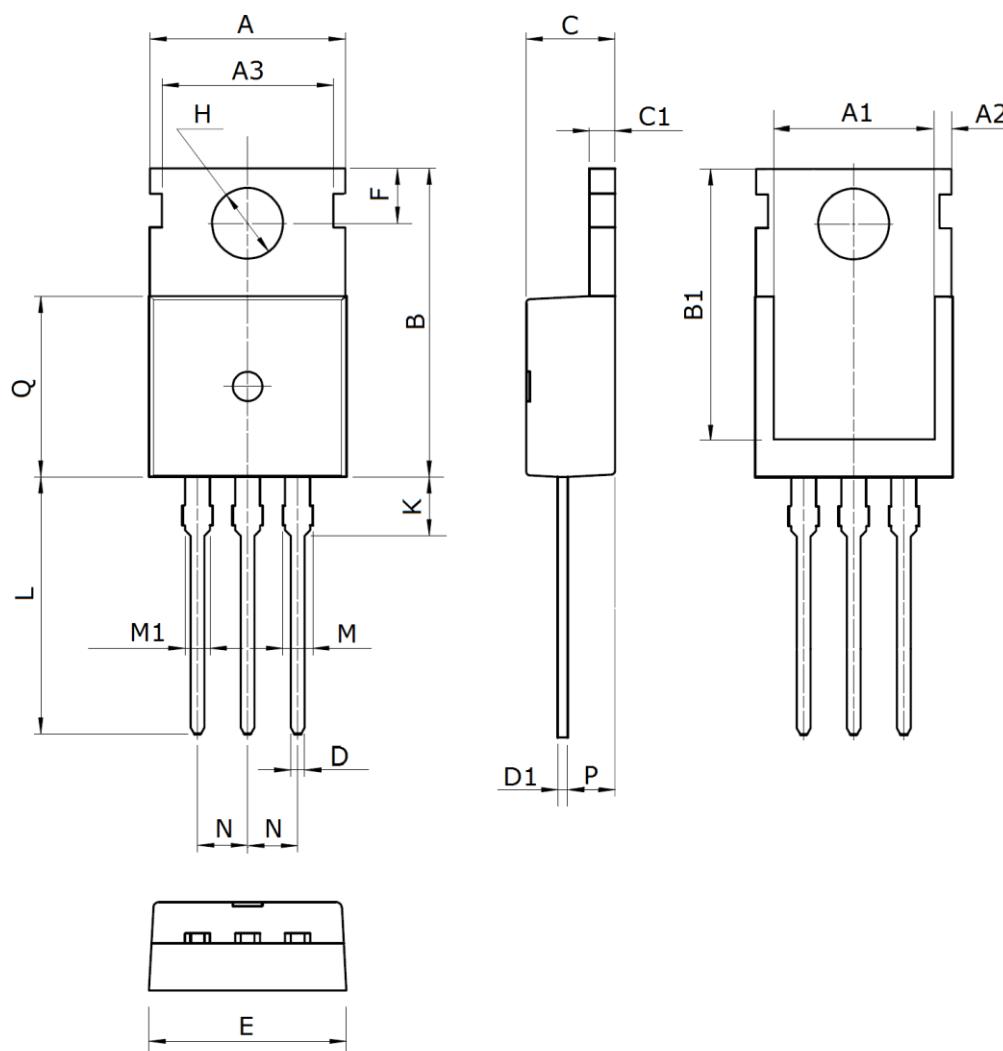


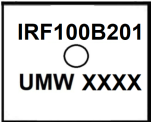
Fig 21. Typical Stored Charge vs. dif/dt

Package Mechanical Data TO-220



Symbol	Dimensions (mm)	Symbol	Dimensions (mm)	Symbol	Dimensions (mm)
A	10.0±0.3	C1	1.3±0.2	L	13.2±0.4
A1	8.0±0.2	D	0.8±0.2	M	1.38±0.1
A2	0.94±0.1	D1	0.5±0.1	M1	1.28±0.1
A3	8.7±0.1	E	10.0±0.3	N	2.54(typ)
B	15.6±0.4	F	2.8 ±0.1	P	2.4±0.3
B1	13.2±0.2	H	3.6±0.1	Q	9.15±0.25
C	4.5±0.2	K	3.1±0.2		

Marking



Ordering information

Order code	Package	Baseqty	Deliverymode
UMW IRF100B201	TO-220	1000	Tube and box